

INTERNATIONAL STANDARD

Sample preparation for measurement of mercury level in fluorescent lamps and low-pressure mercury UV radiation sources



THIS PUBLICATION IS COPYRIGHT PROTECTED
Copyright © 2025 IEC, Geneva, Switzerland

All rights reserved. Unless otherwise specified, no part of this publication may be reproduced or utilized in any form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from either IEC or IEC's member National Committee in the country of the requester. If you have any questions about IEC copyright or have an enquiry about obtaining additional rights to this publication, please contact the address below or your local IEC member National Committee for further information.

IEC Secretariat
3, rue de Varembe
CH-1211 Geneva 20
Switzerland

Tel.: +41 22 919 02 11
info@iec.ch
www.iec.ch

About the IEC

The International Electrotechnical Commission (IEC) is the leading global organization that prepares and publishes International Standards for all electrical, electronic and related technologies.

About IEC publications

The technical content of IEC publications is kept under constant review by the IEC. Please make sure that you have the latest edition, a corrigendum or an amendment might have been published.

IEC publications search - webstore.iec.ch/advsearchform

The advanced search enables to find IEC publications by a variety of criteria (reference number, text, technical committee, ...). It also gives information on projects, replaced and withdrawn publications.

IEC Just Published - webstore.iec.ch/justpublished

Stay up to date on all new IEC publications. Just Published details all new publications released. Available online and once a month by email.

IEC Customer Service Centre - webstore.iec.ch/csc

If you wish to give us your feedback on this publication or need further assistance, please contact the Customer Service Centre: sales@iec.ch.

IEC Products & Services Portal - products.iec.ch

Discover our powerful search engine and read freely all the publications previews, graphical symbols and the glossary. With a subscription you will always have access to up to date content tailored to your needs.

Electropedia - www.electropedia.org

The world's leading online dictionary on electrotechnology, containing more than 22 500 terminological entries in English and French, with equivalent terms in 25 additional languages. Also known as the International Electrotechnical Vocabulary (IEV) online.



IEC 62554

Edition 1.2 2025-02
CONSOLIDATED VERSION

INTERNATIONAL STANDARD

Sample preparation for measurement of mercury level in fluorescent lamps and low-pressure mercury UV radiation sources

INTERNATIONAL
ELECTROTECHNICAL
COMMISSION

ICS 29.140.30

ISBN 978-2-8327-0224-6

Warning! Make sure that you obtained this publication from an authorized distributor.

CONTENTS

FOREWORD.....	4
INTRODUCTION.....	6
INTRODUCTION to Amendment 1	6
1 Scope.....	7
2 Normative references	7
3 Terms and definitions	7
4 General	8
5 Procedure for collecting mercury from a fluorescent lamp.....	8
5.1 General	8
5.2 Reagents.....	9
5.3 Chemical lab ware.....	9
5.4 Sample preparation	9
5.4.1 Cold spotting methods	9
5.4.2 Sample preparation of fluorescent lamps by non-cold-spot (lectroning) methods	11
5.4.3 Sample preparation of fluorescent lamps by non-cold-spot (crushing) methods	12
5.4.4 Nitric acid rinse method for linear fluorescent lamps.....	13
5.4.5 Direct mercury measurement.....	14
5.4.6 Sample preparation of other fluorescent lamps	14
5.5 Sample digestion.....	14
5.5.1 Ambient conditions	14
5.5.2 Glass samples (in 250 ml, 500 ml, 1 000 ml or 2 000 ml container).....	14
5.5.3 Metal samples (in 125 ml container)	14
5.6 Filtering.....	15
6 Measurement	15
6.1 Blank test	15
6.2 Data reporting	15
6.3 Analysis	15
Annex A (informative) Electrothermal vaporization atomic absorption spectrometry (EVAAS) method.....	16
A.1 Electrothermal vaporization atomic absorption spectrometer	16
A.2 Reagents.....	17
A.3 Measurement	17
A.3.1 Sample measurement.....	17
A.3.2 Calibration curve	18
Annex B (informative) Information on the cold spotting method.....	19
B.1 General description of mercury collection by the cold spotting method on both single- and double capped lamps	19
B.1.1 General	19
B.1.2 Double-capped fluorescent lamp.....	19
B.1.3 Single-capped fluorescent lamp.....	19
B.1.4 General	19
B.1.5 Liquid nitrogen treatment of a cold spot.....	19
B.1.6 Extracting the cold spot segment.....	20
B.2 Detailed procedure for condensation of free mercury to the cold spot.....	20
B.2.1 Double-capped lamp.....	20

B.2.2 Single-capped lamp	21
Bibliography	22
Figure A.1 – Configuration of the electrothermal vaporization atomic absorption spectrometry testing apparatus	16
Figure A.2 – An example of the electrothermal vaporization atomic absorption spectrometer test apparatus layout	17
Figure B.1 – Example of glass cell arrangement	20
Figure B.2 – Example of cooling device arrangement.....	21

Currently in preview, click buy full version

INTERNATIONAL ELECTROTECHNICAL COMMISSION

**SAMPLE PREPARATION FOR MEASUREMENT
OF MERCURY LEVEL IN FLUORESCENT LAMPS AND LOW-PRESSURE
MERCURY UV RADIATION SOURCES**

FOREWORD

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
- 2) The formal decisions or agreements of IEC on technical matters express, as nearly as possible, an international consensus of opinion on the relevant subjects since each technical committee has representation from all interested IEC National Committees.
- 3) IEC Publications have the form of recommendations for international use and are accepted by IEC National Committees in that sense. While all reasonable efforts are made to ensure that the technical content of IEC Publications is accurate, IEC cannot be held responsible for the way in which they are used or for any misinterpretation by any end user.
- 4) In order to promote international uniformity, IEC National Committees undertake to apply IEC Publications transparently to the maximum extent possible in their national and regional publications. Any divergence between any IEC Publication and the corresponding national or regional publication shall be clearly indicated in the latter.
- 5) IEC itself does not provide any attestation of conformity. Independent certification bodies provide conformity assessment services and, in some areas, access to IEC marks of conformity. IEC is not responsible for any services carried out by independent certification bodies.
- 6) All users should ensure that they have the latest edition of this publication.
- 7) No liability shall attach to IEC or its directors, employees, servants or agents including individual experts and members of its technical committees and IEC National Committees for any personal injury, property damage or other damage of any nature whatsoever, whether direct or indirect, or for costs (including legal fees) and expenses arising out of the publication, use of, or reliance upon, this IEC Publication or any other IEC Publications.
- 8) Attention is drawn to the Normative references cited in this publication. Use of the referenced publications is indispensable for the correct application of this publication.
- 9) IEC draws attention to the possibility that the implementation of this document may involve the use of (a) patent(s). IEC takes no position concerning the evidence, validity or applicability of any claimed patent rights in respect thereof. As of the date of publication of this document, IEC had received notice of (a) patent(s), which may be required to implement this document. However, implementers are cautioned that this may not represent the latest information, which may be obtained from the patent database available at <https://patents.iec.ch>. IEC shall not be held responsible for identifying any or all such patent rights.

This consolidated version of the official IEC Standard and its amendment has been prepared for user convenience.

IEC 62554 edition 1.2 contains the first edition (2011-08) [documents 34A/1484/FDIS and 34A/1502/RVD], its amendment 1 (2017-10) [documents 34A/1997/CDV and 34A/2028/RVC] and its amendment 2 (2025-02) [documents 34A/2398/CDV and 34A/2427/RVC].

In this Redline version, a vertical line in the margin shows where the technical content is modified by amendments 1 and 2. Additions are in green text, deletions are in strikethrough red text. A separate Final version with all changes accepted is available in this publication.

International Standard IEC 62554 has been prepared by subcommittee 34A: Lamps, of IEC technical committee 34: Lamps and related equipment.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of this document and its amendments will remain unchanged until the stability date indicated on the IEC website under webstore.iec.ch in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn, or
- revised.

Currently in preview, click buy full version.

INTRODUCTION

The International Electrotechnical Commission (IEC) draws attention to the fact that it is claimed that compliance with this document may involve the use of a patent concerning Cold spotting given in 5.4.1.

IEC takes no position concerning the evidence, validity and scope of this patent right.

The holder of this patent right has assured the IEC that he/she is willing to negotiate licences free of charge with applicants throughout the world. In this respect, the statement of the holder of this patent right is registered with IEC. Information may be obtained from:

General Electric Company

Appliance Park AP35-1002, Louisville, KY, 40225-0001, US

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights other than those identified above. IEC shall not be held responsible for identifying any or all such patent rights.

ISO (www.iso.org/patents) and IEC (<http://patents.iec.ch>) maintain online data bases of patents relevant to their standards. Users are encouraged to consult the data bases for the most up to date information concerning patents.

According to IEC SMB 136/7 decision, the technical committee decided to remove designation of a reference method.

INTRODUCTION to Amendment 1

IEC 62554 specifies the method of sample preparation for the measurement of mercury level in fluorescent lamps. It refers to IEC 62321:2008 for the technique for determining the amount of mercury.

In the meantime it has been found that for fluorescent lamps, some of the techniques specified in IEC 62321 can lead to inaccurate and misleading results and in addition this standard has been split into several parts.

In bilateral discussions between members of subcommittee 34A and technical committee 111, it was agreed to update the relevant part of IEC 62321 and the reference made to it in IEC 62554. Amendment 1 to IEC 62321-4 has now been published (IEC 62321-4:2013/AMD1:2017).

SAMPLE PREPARATION FOR MEASUREMENT OF MERCURY LEVEL IN FLUORESCENT LAMPS AND LOW-PRESSURE MERCURY UV RADIATION SOURCES

1 Scope

This International Standard specifies sample preparation methods for determining mercury levels in new tubular fluorescent lamps (including single capped, double capped, self-ballasted and cold cathode fluorescent lamp (CCFL) for backlighting) and new low-pressure mercury UV radiation sources, containing 0,1 mg mercury or more. The intended resolution of the methods described in this ~~standard~~ document is of the order of 5 %.

Mercury level measurement of spent lamps is excluded, as during lamp operation, mercury gradually diffuses into the glass wall and reacts with the glass materials. The test method of this standard does not recover mercury that is diffused into or reacted with or otherwise incorporated irreversibly with the glass wall of discharge tubes.

This standard does not contain information on measurement. Measurement is specified in IEC 62321.

2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

ISO/IEC 17025:2005, *General requirements for the competence of testing and calibration laboratories*

~~IEC 62321:2008, *Electrotechnical products – Determination of levels of six regulated substances (lead, mercury, cadmium, hexavalent chromium, polybrominated biphenyls, polybrominated diphenyl ethers)*~~

IEC 62321-4:2013, *Determination of certain substances in electrotechnical products – Part 4: Mercury in polymers, metals and electronics by CV-AAS, CV-AFS, ICP-OES and ICP-MS*
IEC 62321-4:2013/AMD1:2017

ISO 3696:1987, *Water for analytical laboratory use – Specification and test methods*

3 Terms and definitions

For the purposes of the present document, the following terms and definitions apply.

3.1

new lamp

a lamp that has not been energized since manufacture

3.2

cold cathode fluorescent lamp (CCFL) for backlighting

small diameter fluorescent lamp having cold cathode in the lamp, in which most of light is emitted by the excitation of phosphors coated in discharge tube and used as backlight in LCD